## PATENT COOPERATION TREATY

# **PCT**

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INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY
(Chapter II of the Patent Cooperation Treaty)

(PCT Article 36 and Rule 70)

Applicant's or agent's file reference	EOD EXPORTED A CO		
66054010PCT	FOR FURTHER AC	TION	See Form PCT/IPEA/416
International application No.	International filing date (	day/month/year)	Priority date (day/month/year)
PCT/US04/25332 06 August 2004 (06.08.2004) 06 August 2003 (06.08.2003)			06 August 2003 (06.08.2003)
International Patent Classification (IPC) or national classification and IPC			
IPC: Please See Continuation Sheet USPC: 216/2;250/307;252/518.1;435/4	1;438/14;528/380	· · · · · · · · · · · · · · · · · · ·	
Applicant			
IMAGO SCIENTIFIC INSTRUMENTS			
This report is the internat     Examining Authority unde	ional preliminary exami r Article 35 and transmit	ination report, establi ted to the applicant ac	ished by this International Preliminary cording to Article 36.
2. This REPORT consists of	a total of sheets, incl	uding this cover sheet	
3. This report is also accomp	anied by ANNEXES, co	mprising:	
a. (sent to the applica	nt and to the Internation	al Bureau) a total of	sheets, as follows:
sheets of the this report ar	description, claims and/	or drawings which harectifications authorize	ve been amended and are the basis of ed by this Authority (see Rule 70.16
that goes bey	supersede earlier sheets, ond the disclosure in the d the Supplemental Box.	but which this Author international application	ority considers contain an amendment tion as filed, as indicated in item 4 of
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, containin	ig a sequence listing at Supplemental Box Re	nd/or tables related i	thereto, in electronic form only, as Listing (see Section 802 of the
4. This report contains indica	tions relating to the follo	wing items:	
K-ZI	asis of the report	······g recine.	
Box No. II Priority			
Box No. III Non-establishment of opinion with regard to novelty, inventive step and industrial applicability			
<del></del>	ck of unity of invention		
		. A.di.l. 25(2)	
Box No. V Reasoned statement under Article 35(2) with regard to novelty, inventive step of industrial applicability; citations and explanations supporting such statement			
· • • • • • • • • • • • • • • • • • • •	rtain documents cited		supplied the supplied that the supplied the
Box No. VII Ce	rtain defects in the intern	national application	
Box No. VIII Ce	Box No. VIII Certain observations on the international application		
Date of submission of the demand		Date of completion of	
21 October 2005 (21.10.2005)		21 1 2006 (21 06 20	000
Name and mailing address of the IPEA/ U	S	21 June 2006 (21.06.20	
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Commissioner for Patents P.O. Box 1450		Susan E. Fernandez	gance 1500
Alexandria, Virginia 22313-1450			Janese Ford
Facsimile No. (571) 273-3201 Form PCT/IPEA/409 (cover sheet)(April 20	)()(5)	Telephone No. (571) 2	2/2-1600

International	application	No.

PCT/US04/25332

Box No. I Basis of the report
1. With regard to the language, this report is based on:
the international application in the language in which it was filed.
a translation of the international application into, which is the language of a translation furnished for the purposes of:
international search (under Rules 12.3 and 23.1(b))
publication of the international application (under Rule 12.4(a))
international preliminary examination (under Rules 55.2(a) and/or 55.3(a))
2. With regard to the elements of the international application, this report is based on (replacement sheets which have been furnished to the receiving Office in response to an invitation under Article 14 are referred to in this report as "originally filed" and are not annexed to this report):
the international application as originally filed/furnished
the description:
pages 1-44 as originally filed/furnished
pages* NONE received by this Authority on  pages* NONE received by this Authority on
N7
the claims:
pages NONE as originally filed/furnished
pages* NONE as amended (together with any statement) under Article 19 pages* 45-48 received by this Authority on 21 October 2005 (21.10.2005)
pages* NONE received by this Authority on 21 October 2005 (21.10.2005)
the drawings:
pages 1/20-20/20 as originally filed/furnished
pages* NONE received by this Authority on  pages* NONE received by this Authority on
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a sequence listing and/or any related table(s) - see Supplemental Box Relating to Sequence Listing.
3. The amendments have resulted in the cancellation of:
the description, pages
the claims, Nos. 29
the drawings, sheets/figs
the sequence listing (specify):
any table(s) related to the sequence listing (specify):
4. This report has been established as if (some of) the amendments annexed to this report and listed below had not been made, since they have been considered to go beyond the disclosure as filed, as indicated in the Supplemental Box (Rule 70.2(c)).
the description pages
the description, pages
the claims, Nos.
the drawings, sheets/figs
the sequence listing (specify):
any table(s) related to the sequence listing (specify):
* If itam d applies some on all of the solutions have been all a
* If item 4 applies, some or all of those sheets may be marked "superseded."  orm PCT/IPEA/409 (Box No. I) (April 2005)

Form PCT/IPEA/409 (Box No. V) (April 2005)

International application No. PCT/US04/25332

Claims   1,13,14,17,20-22 and 25-28   N	Claims 1,13,14,17,20-22 and 25-28 N  Inventive Step (IS) Claims 8-11,15,18,23 Y  Claims 1-7,12-14,16,17,19-22 and 24-28 N  Industrial Applicability (IA) Claims 1-28 Y	Statement	·	
Claims   1,13,14,17,20-22 and 25-28   N	Claims   1,13,14,17,20-22 and 25-28   N	Novelty (N)	Claims 2-12,15,16,18,19,23 and 24	Y
Claims   1-7,12-14,16,17,19-22 and 24-28   N     Industrial Applicability (IA)   Claims   1-28   Y     Claims   NONE   N     Citations and Explanations (Rule 70.7)	Claims 1-7,12-14,16,17,19-22 and 24-28 N  Industrial Applicability (IA) Claims 1-28 Y  Claims NONE N  Citations and Explanations (Rule 70.7)			N
Claims   1-7,12-14,16,17,19-22 and 24-28   N     Industrial Applicability (IA)   Claims   1-28   Y     Claims   NONE   N     Citations and Explanations (Rule 70.7)	Claims 1-7,12-14,16,17,19-22 and 24-28  Industrial Applicability (IA)  Claims 1-28  Claims NONE  Citations and Explanations (Rule 70.7)	Inventive Step (IS)	Claims 8-11,15,18,23	Y
Claims NONE N  Citations and Explanations (Rule 70.7)	Claims NONE N  Citations and Explanations (Rule 70.7)			N
Claims NONE N  Citations and Explanations (Rule 70.7)	Claims NONE N  Citations and Explanations (Rule 70.7)	Industrial Applicability (IA)	Claims 1-28	YI
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Continuation of:

Continuation of IPC:

 $\textbf{C08G 75/00(}\ 2006.01); \textbf{C12Q }\ 1/00(\ 2006.01); \textbf{C23F }\ 1/00(\ 2006.01); \textbf{G01N }\ 23/00(\ 2006.01); \textbf{G01R }\ 31/26(\ 2006.01); \textbf{G21K }\ 7/00(\ 2006.01); \textbf{H01B }\ 1/02(\ 2006.01), 1/08(\ 2006.01); \textbf{H01L }\ 21/66(\ 2006.01)$ 

### V. 2. Citations and Explanations:

Claims 1, 13-14, 17, 20-22, and 25-28 lack novelty under PCT Article 33(2) as being anticipated by Kelly et al. (US 2001/0044156 A1). Kelly et al. teaches methods of sampling specimens for microanalysis wherein a study specimen is embedded in a larger study object (the matrix) to yield an embedded specimen. Focused ion beam lithography may be used, and biological materials may be applied. The prepared specimen is well suited for atom probe microanalysis. Thus, the above claims are anticipated.

Claims 1-6, 12-14, 16, 17, 19-22, and 24-28 lack an inventive step under PCT Article 33(3) as being obvious over Kelly et al. (US 2001/0044156 A1) in view of Ban et al. Kelly et al. teaches methods of sampling specimens for microanalysis wherein a study specimen is embedded in a larger study object (the matrix) to yield an embedded specimen. Focused ion beam lithography may be used, and biological materials may be applied. The prepared specimen is well suited for atom probe microanalysis. Kelly et al. does not require that the study specimen is embedded within a polymer matrix. Ban et al. teaches the development of multi-phase polymer blends wherein osmium tetroxide and ruthenium tetroxide staining is applied, which aids in the detection of polymer domains. It would have been obvious to one of ordinary skill in the art to have modified the Kelly invention such that the matrix is treated as discussed in Ban et al., since the methods of Ban et al. allowed for successful detection of polymer domains. Moreover, the presence of osmium tetroxide and ruthenium tetroxide staining inherently increases the conductivity of the polymer matrix.

Claims 1-7, 12-14, 16, 17, 19-22, and 24-28 lack an inventive step under PCT Article 33(3) as being obvious over the prior art as applied in last paragraph and further in view of van der Linden et al. Kelly et al. and Ban et al. do not disclose embedding the specimen in hydrogel. van der Linden et al. discloses fabrication of hydrogels with photopatterns. It would have been obvious to one of ordinary skill in the art to have modified the invention rendered obvious by Kelly et al. and Ban et al. such that the specimen is embedded in hydrogel, since hydrogel is highly flexible and is easy to manufacture.

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Claims 8-11, 15, 18, and 23 meet the criteria set out in PCT Article 33(2)-(3), because the prior art does not teach or fairly suggest the process by which the specimen is embedded within the electrically conductive polymer matrix, a polymer matrix comprising polythiophenes, polyanilines, or polypyrroles, doping the embedded specimen or specimen-coated substrate, or the stabilization of the specimen by cross-links.

Claims 1-28 meet the criteria set out in PCT Article 33(4), and thus have industrial applicability because the subject matter claimed can be made or used in industry.

With regard to applicant's amendments/remarks filed October 21, 2005, it is noted that the polymer matrix of Ban et al. would have been a suitable, electrically conductive matrix for embedding the specimen since its domains are detectable, which would mean that any specimen embedded in the detectable polymer domain would also have been detectable based on the polymer domain. Though Ban et al. does not teach embedding a specimen in a matrix or the forming regions on the embedded specimen into shapes suitable for microanalysis by an atom probe, Kelly et al. teaches these embodiments. With regard to the arguments that the polymer matrix of Ban et al. is not treated to increase its conductivity, it is respectfully noted that Ban et al. teaches treating the polymer matrix with osmium tetroxide and ruthenium tetroxide, which inherently increases the conductivity of the polymer matrix.
NEW CITATIONS

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#### **CLAIMS**

### What is claimed is:

- 1. A method of preparing a specimen for microanalysis, the method comprising:
- (a) embedding the specimen within an electrically conductive polymer matrix to yield an embedded specimen; and
- (b) forming regions on the embedded specimen into shapes suitable for microanalysis by an atom probe.
- 2. The method of claim 1, wherein in step (a), the specimen is embedded within an intrinsically conductive polymer matrix.
- 3. The method of claim 1, wherein in step (a), the specimen is embedded within a polymer matrix and further comprising a step of treating the polymer matrix to increase its conductivity.
- 4. The method of claim 3, wherein the polymer matrix is treated with a metal-containing compound, wherein the treatment increases the conductivity of the polymer matrix.
- 5. The method of claim 3, wherein the polymer matrix is treated with a metal-containing compound selected from a group consisting of osmium-containing compounds and ruthenium-containing compounds.
- 6. The method of claim 3, wherein the polymer is treated with a metal-containing compound selected from a group consisting of osmium tetroxide and ruthenium tetroxide.
- 7. The method of claim 1, wherein in step (a), the specimen is embedded within a hydrogel.

- 8. The method of claim 1, wherein in step (a), the specimen is embedded within the electrically conductive polymer matrix by mixing the specimen with a corresponding monomeric compound and then polymerizing the monomeric compound to yield the electrically conductive polymer matrix.
- 9. The method of claim 1, wherein in step (a), the specimen is embedded within the electrically conductive polymer matrix by mixing the specimen with a corresponding pre-polymer compound and then polymerizing the pre-polymer compound to yield the electrically conductive polymer matrix.
- 10. The method of claim 1, wherein in step (a), the specimen is embedded within the electrically conductive polymer matrix by mixing the specimen with a corresponding water-soluble monomeric compound and then polymerizing the monomeric compound in aqueous solution to yield the electrically conductive polymer matrix.
- 11. The method of claim 1, wherein in step (a), the specimen is embedded within a matrix comprising a polymer selected from a group consisting of polythiophenes, polyanilines, polypyrroles, and combinations thereof.
- 12. The method of claim 1, wherein in step (a), the embedded specimen is disposed on a substrate prior to step (b).
- 13. The method of claim 1, wherein in step (a), the embedded specimen is disposed on a substrate after step (b).
- 14. The method of claim 1, wherein in step (b), the regions are formed using focused ion beam lithography.
- 15. The method of claim 1, wherein in step (b), the regions are formed by doping the embedded specimen with a masking agent and then exposing the embedded specimen to a broad ion beam under conditions and for a time sufficient to remove the masking agent from the embedded

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specimen, whereby regions protruding from embedded specimen and suitable for microanalysis by an atom probe are formed.

- 16. The method of claim 1, wherein in step (a), the embedded specimen is disposed on a substrate prior to step (b) to yield a specimen-coated substrate, and then, in step (b), forming regions on the specimen-coated substrate suitable for microanalysis by an atom probe.
- 17. The method of claim 16, wherein in step (b), the regions are formed using focused ion beam lithography.
- 18. The method of claim 1, wherein in step (b), the regions are formed by doping the specimen-coated substrate with a masking agent and then exposing the specimen-coated substrate to a broad ion beam under conditions and for a time sufficient to remove the masking agent from the embedded specimen, whereby regions protruding from embedded specimen and suitable for microanalysis by an atom probe are formed.
- 19. The method of claim 1, wherein in step (a), an organic or biological specimen is embedded within the matrix.
- 20. The method of claim 1, wherein a protein is embedded within the matrix.
- 21. The method of claim 1, further comprising the steps of forming regions on a substrate suitable for microanalysis by an atom probe, and immobilizing the embedded specimen on the formed regions of the substrate, whereby regions on the embedded specimen are formed into shapes suitable for microanalysis by an atom probe.
- 22. The method of claim 1, further comprising the steps of forming regions on a substrate suitable for microanalysis by an atom probe, and immobilizing the specimen on the formed regions of the substrate, and then

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coating the formed regions of the substrate with the electrically conductive matrix, whereby the specimen is embedded within the matrix.

- 23. The method of claim 1, further comprising stabilizing the specimen by forming internal cross-links within the specimen, by forming cross-links between the specimen and the matrix, by forming cross-links between the specimen and a substrate, or combinations thereof.
- 24. The method according to any one of the preceding claims, further comprising step (c): and then microanalyzing the shapes formed in step (b).
- 25. The method of claim 24, wherein in the shapes are microanalyzed by atom probe microscopy.
- 26. The method of claim 24, wherein in the shapes are microanalyzed by local electrode atom probe microscopy.
- 27. An atom probe specimen fabricated by a method according to any one of claims 1 to 24.
- 28 A composition of matter comprising an intrinsically conductive polymer whose conductivity has been altered by contact with a compound selected from a group consisting of osmium tetroxide, ruthenium tetroxide, and combinations thereof.